## Notice of References Cited Application/Control No. 10/606,045 Examiner /BINH K. TIEU/ Applicant(s)/Patent Under Reexamination LYNCH ET AL. Page 1 of 1

## U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US- 20050180343	08-2005	Van Valkenburg	370/310
*	В	US-2003/0149794	08-2003	MORRIS et al.	709/249
*	C	US-2002/0075941	06-2002	Souissi et al.	375/133
*	D	US-2003/0139179	07-2003	Fuchs et al.	455/426
	Е	US-			
	F	US-			
	G	US-			
	Η	US-			
	_	US-			
	7	US-			
	ĸ	US-			
	٦	US-			
	М	US-			

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
<u> </u>	0					
	Р					
	Q					
	R					
	S					
	Т					

## **NON-PATENT DOCUMENTS**

_						
*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)				
	U					
	V					
	w					
	x					

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.